



NIP-188

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FEB 26 2003  
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

H. AKIYAMA et al

Serial No. 09/623,040

Group Art Unit: 2878

Filed: August 25, 2000

For: CHARGED PARTICLE BEAM IRRADIATION EQUIPMENT  
AND CONTROL METHOD THEREOF

SECOND PRELIMINARY AMENDMENT

Assistant Commissioner of Patents  
Washington, D.C. 20231

Sir:

Prior to examination, please amend the above-identified  
application as follows.

IN THE CLAIMS

Please cancel claims 9 and 10 without prejudice or  
disclaimer, and rewrite claim 4 as follows.

C<sub>1</sub> 4. (Once Amended) A charged particle beam irradiation  
equipment, for applying a charged particle beam to an  
irradiation area, comprising a scanning electromagnet for  
deflecting the charged particle beam and a power supply for  
applying a voltage to the scanning electromagnet,  
characterized in that

the power supply comprises;